

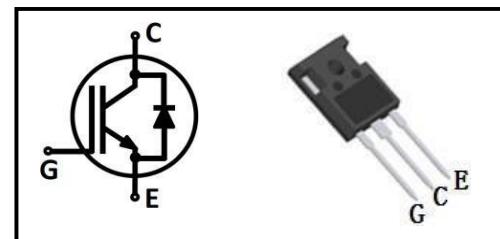
特征/Features

- 饱和压降为正温度系数，易于并联使用
Easy parallel switching capability due to positive temperature coefficient in V_{CEsat}
- 低饱和压降，快速开关
Low V_{CEsat} , fast switching
- 高可靠性及热稳定性，良好的参数一致性
High ruggedness, good thermal stability very tight parameter distribution

应用领域/Applications

- 空气压缩机/Climate Compressor
- 不间断电源/UPS
- 功率因数校正/PFC
- PTC加热器/PTC Heater

型号/Type	打标/Marking	封装/Package
QMWF50N65E	QM50N65E	TO-247



最大额定值/Maximum Rated Values¹

Item	Symbol	Value	Unit
集电极-发射极电压 Collector-emitter voltage	V_{CE}	650	V
集电极电流 DC collector current ²	I_C	80	
$T_C=25^\circ\text{C}$		50	
$T_C=100^\circ\text{C}$			
集电极脉冲电流 Pulsed collector current ³	I_{Cpuls}	200	
二极管正向电流 Diode forward current ²	I_F	80	
$T_C=25^\circ\text{C}$		50	
$T_C=100^\circ\text{C}$			
二极管脉冲电流 Diode pulsed current ³	I_{Fpuls}	200	
栅极-发射极电压 Gate-emitter voltage	V_{GE}	± 20	V
瞬态栅极-发射极电压 Transient Gate-emitter voltage ($t_p \leq 10\mu\text{s}$)		± 30	
耗散功率 Power dissipation	P_{tot}	300	W
$T_C=25^\circ\text{C}$		150	
$T_C=100^\circ\text{C}$			
工作结温 Operating junction temperature	T_j	-55~175	$^\circ\text{C}$
储存温度 Storage temperature	T_{stg}	-55~150	

1: Reference standard: JESD-022 ;

2: limited by T_{jmax} ;

3: T_p limited by T_{jmax} ;

电学特性/Electrical Characteristics

静态特性/Static Characteristics (at $T_j=25^\circ\text{C}$ unless otherwise specified)

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
集电极-发射极击穿电压 Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0V, I_c=0.25mA$	650	-	-	
集电极-发射极饱和电压 Collector-emitter saturation voltage	$V_{CE(\text{sat})}$	$V_{GE}=15V, I_c=50A$ $T_j=25^\circ\text{C}$	-	1.60	1.90	V
		$T_j=125^\circ\text{C}$	-	1.72	-	
		$T_j=150^\circ\text{C}$	-	1.80	-	
二极管正向压降 Diode forward voltage	V_F	$V_{GE}=0V, I_F=50A$ $T_j=25^\circ\text{C}$	-	1.65	1.95	
		$T_j=125^\circ\text{C}$	-	1.57	-	
		$T_j=150^\circ\text{C}$	-	1.53	-	
阈值电压 G-E threshold voltage	$V_{GE(th)}$	$I_c=1mA, V_{CE}=V_{GE}$	4.5	5.5	6.5	
集电极-发射极漏电流 C-E leakage current	I_{CES}	$V_{CE}=650V, V_{GE}=0V$ $T_j=25^\circ\text{C}$	-	-	0.01	mA
		$T_j=150^\circ\text{C}$	-	-	1.0	
栅极-发射极漏电流 G-E leakage current	I_{GES}	$V_{CE}=0V, V_{GE}=20V$	-	-	250	nA
跨导 Transconductance	g_{FS}	$V_{CE}=20V, I_c=50A$	-	21	-	s

动态特性/Dynamic Characteristics

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
输入电容 Input capacitance	C_{iss}	$V_{CE}=25V, V_{GE}=0V, f=1MHz$	-	5810	-	pF
输出电容 Output capacitance	C_{oss}		-	130	-	
反馈电容 Reverse transfer capacitance	C_{rss}		-	65	-	
栅电荷 Gate charge	Q_G	$V_{cc}=300V, I_c=50A, V_{GE}=15V$	-	230	-	nC

热学特性/Thermal Characteristics

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
结-外壳热阻 IGBT thermal resistance, junction-case	R_{thJC}	$-$	-	-	0.5	K/W
二极管结-外壳热阻 Diode thermal resistance, junction-case	R_{thJCD}		-	-	0.65	
结-环境热阻 Thermal Resistance, junction- ambient	R_{thJA}		-	-	40	

二极管开关特性/Diode Characteristics

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
反向恢复时间 Diode reverse recovery time	t_{rr}	$T_J=25\text{ }^\circ\text{C}, V_R=400V, I_F=50A, dI/dt=600A/\mu\text{s}$	-	105	-	ns
反向恢复电荷 Diode reverse recovery charge	Q_{rr}		-	0.96	-	μC
反向恢复峰值电流 Diode peak reverse recovery current	I_{rrm}		-	14.8	-	A
反向恢复时间 Diode reverse recovery time	t_{rr}	$T_J=150\text{ }^\circ\text{C}, V_R=400V, I_F=50A, dI/dt=600A/\mu\text{s}$	-	150	-	ns
反向恢复电荷 Diode reverse recovery charge	Q_{rr}		-	3.05	-	μC
反向恢复峰值电流 Diode peak reverse recovery current	I_{rrm}		-	33	-	A

IGBT开关特性(感性负载)/IGBT Switching Characteristics

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
开通延迟时间 Turn-on delay time	$t_{d(on)}$	$T_J=25\text{ }^\circ\text{C}, V_{cc}=400V, I_C=50A, V_{GE}=0/15V, R_G=10\Omega, \text{Inductive load}$	-	89	-	ns
上升时间 Rise time	t_r		-	62	-	
关断延迟时间 Turn-off delay time	$t_{d(off)}$		-	265	-	
下降时间 Fall time	t_f		-	47	-	
开通损耗 Turn-on energy	E_{on}		-	1.20	-	mJ
关断损耗 Turn-off energy	E_{off}		-	1.12	-	
开关损耗 Total switching energy	E_{ts}		-	2.32	-	
开通延迟时间 Turn-on delay time	$t_{d(on)}$	$T_J=150\text{ }^\circ\text{C}, V_{cc}=400V, I_C=50A, V_{GE}=0/15V, R_G=10\Omega, \text{Inductive load}$	-	91	-	ns
上升时间 Rise time	t_r		-	63	-	
关断延迟时间 Turn-off delay time	$t_{d(off)}$		-	302	-	
下降时间 Fall time	t_f		-	55	-	
开通损耗 Turn-on energy	E_{on}		-	1.91	-	mJ
关断损耗 Turn-off energy	E_{off}		-	1.33	-	
开关损耗 Total switching energy	E_{ts}		-	3.24	-	

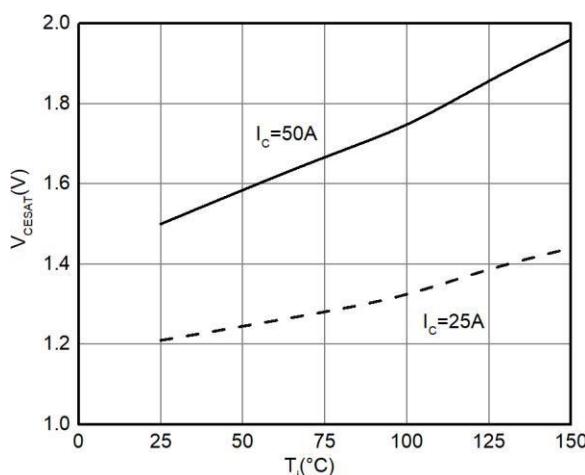


Figure 1. V_{CESAT} 作为结温的函数曲线/
 V_{CESAT} as a function of junction temperature
 $(V_{GE}=15V)$

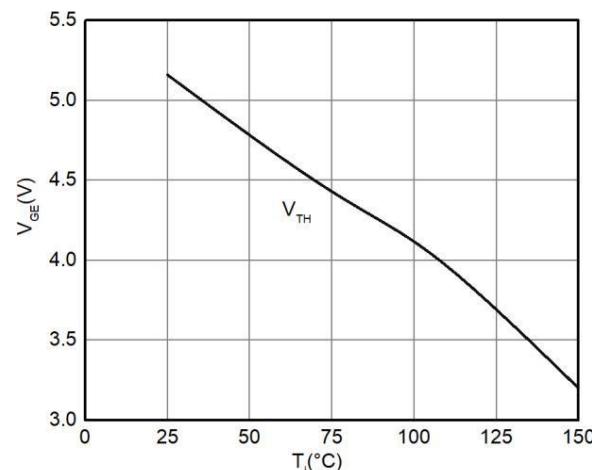


Figure 2. V_{TH} 与结温的关系曲线/
 V_{TH} as a function of junction temperature
 $(I_{CE}=250\mu A)$

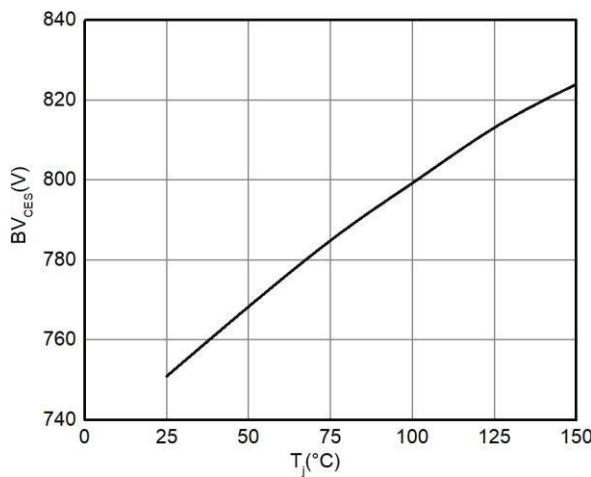


Figure 3. BV作为结温的函数曲线/
BV as a function of junction temperature
 $(I_{CE}=250\mu A)$

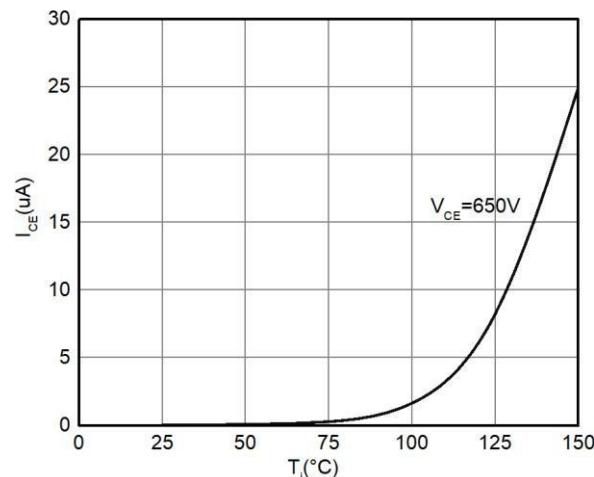


Figure 4. I_{CE}漏电流与结温的关系曲线/
I_{CE} leakage current as a function of junction temperature

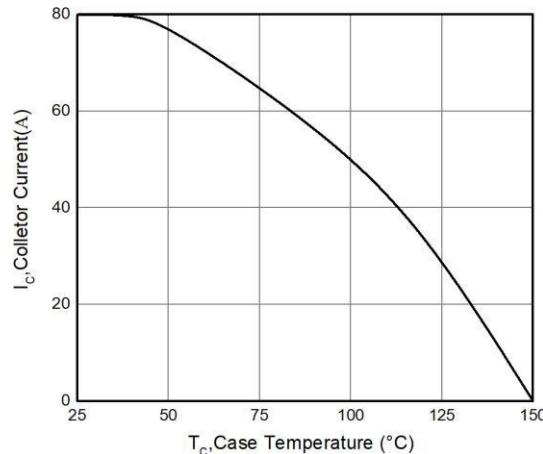


Figure 5. 集电极电流与外壳温度的关系/
Collector current as a function
of case temperature($V_{GE}\geq 15V$, $T_j\leq 150^{\circ}C$)

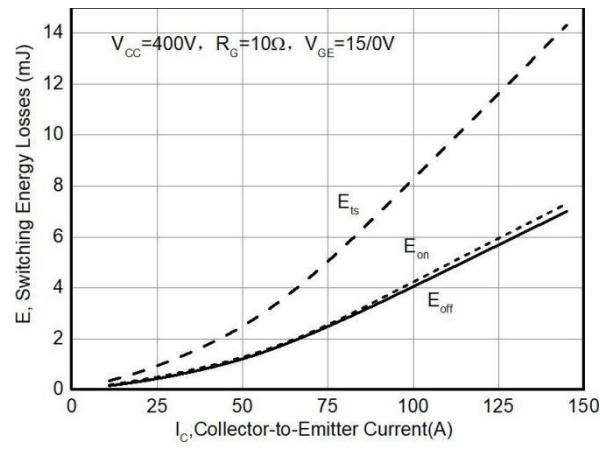
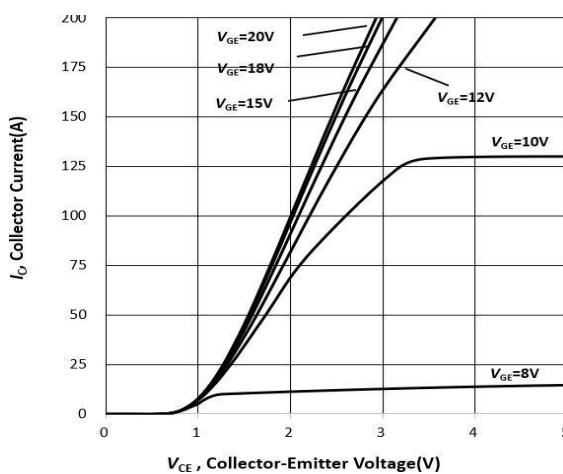
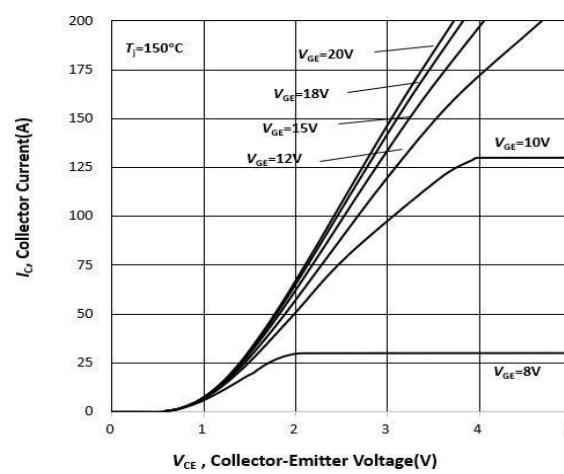


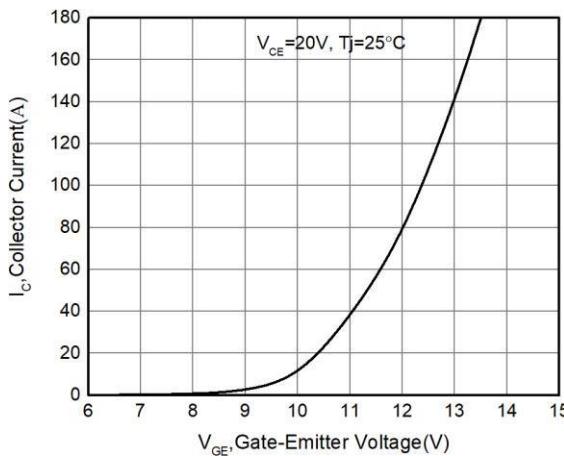
Figure 6 .E_{on}, E_{off} 作为 I_c 的函数曲线/
E_{on}, E_{off} as a function of I_c ($T_j=25^{\circ}C$)



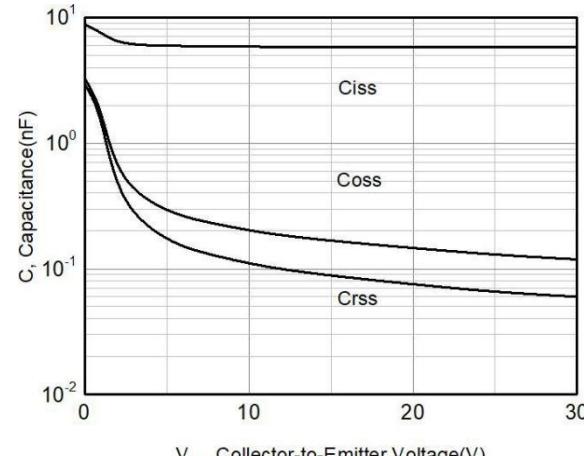
**Figure 7. 典型输出特性/
Typical output characteristic ($T_j = 25^\circ\text{C}$)**



**Figure 8. 典型输出特性/
Typical output characteristic ($T_j = 150^\circ\text{C}$)**



**Figure 9. 典型传输特性/
Typical transfer characteristic ($T_j = 25^\circ\text{C}$)**



**Figure 10. 电容特性/
Capacitance characteristic
($V_{GE} = 0\text{V}$, $f = 1\text{MHz}$)**

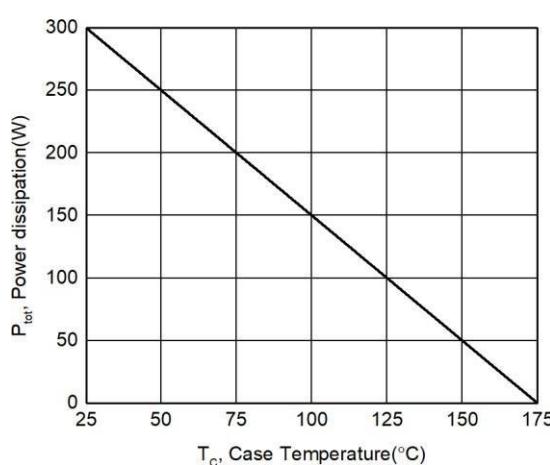
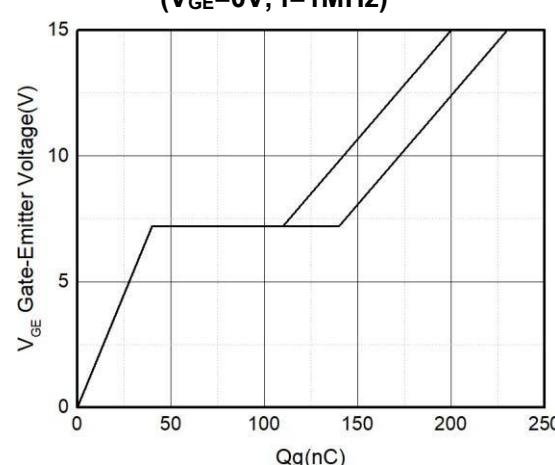


Figure 11. 功耗与外壳温度的关系曲线/Power dissipation as a function of case temperature ($T_j \leq 175^\circ\text{C}$)



**Figure 12. 典型栅极电荷/
Typical gate charge ($I_c = 50\text{A}$)**

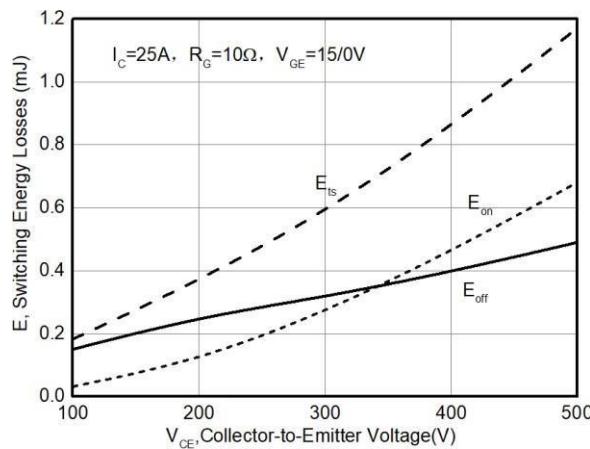


Figure 13. E_{on}, E_{off} 作为 V_{CE} 的函数曲线
 $/E_{on}, E_{off}$ as a function of V_{CE} ($T_j=25^\circ C$)

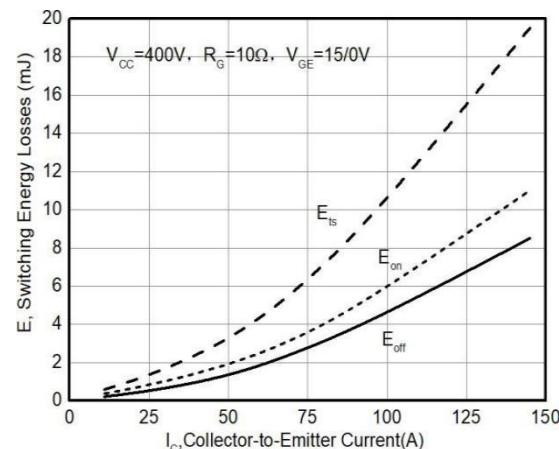


Figure 14. E_{on}, E_{off} 作为 I_C 的函数曲线
 $/E_{on}, E_{off}$ as a function of I_C ($T_j=150^\circ C$)

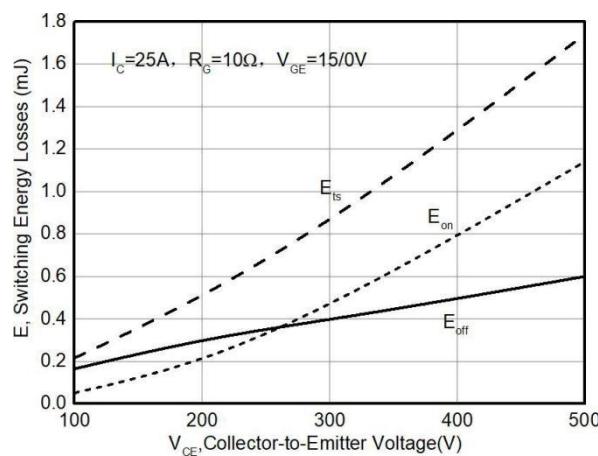


Figure 15. E_{on}, E_{off} 作为 V_{CE} 的函数曲线/
 E_{on}, E_{off} as a function of V_{CE} ($T_j=150^\circ C$)

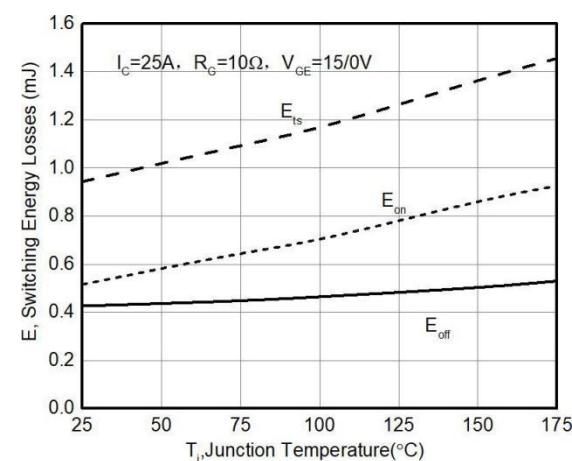


Figure 16. E_{on}, E_{off} 作为结温的函数/ E_{on}, E_{off} as a function of junction temperature

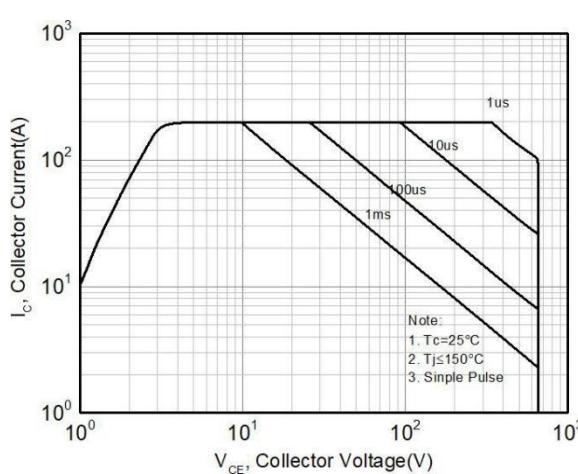
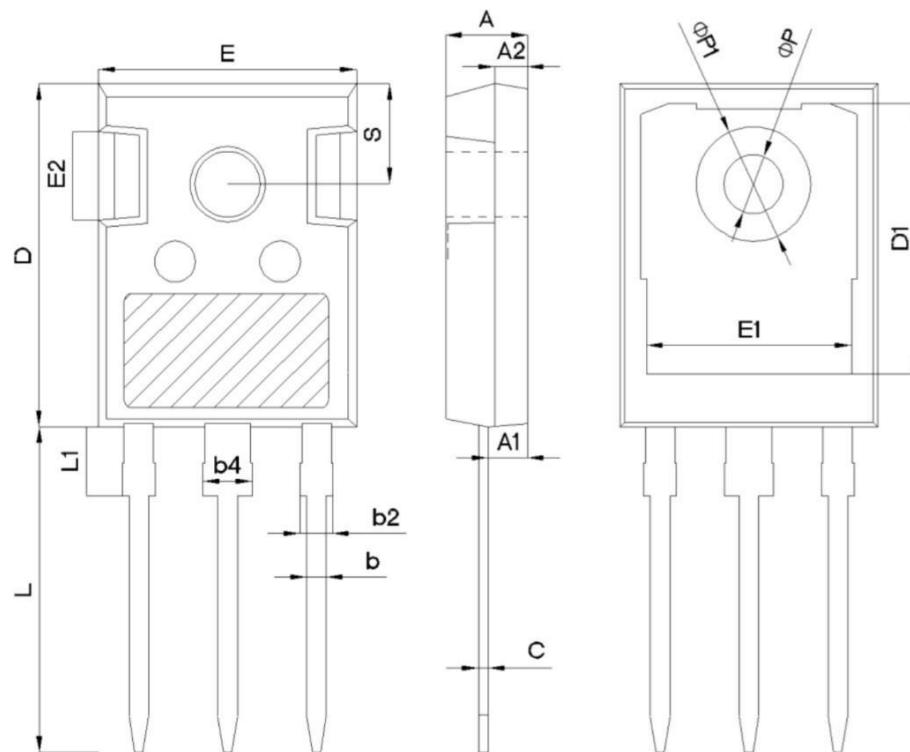


Figure 17. 正偏安全工作区/FBSOA

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SYMBOL	mm		
	MIN	NOM	MAX
A	4.80	5.00	5.20
A1	2.21	2.41	2.61
A2	1.85	2.00	2.15
b	1.11	1.21	1.36
b2	1.91	2.01	2.21
b4	2.91	3.01	3.21
c	0.51	0.61	0.75
D	20.70	21.00	21.30
D1	16.25	16.55	16.85
E	15.50	15.80	16.10
E1	13.00	13.30	13.60
E2	4.80	5.00	5.20
E3	2.30	2.50	2.70
e	5.44BSC		
L	19.62	19.92	20.22
L1	-	-	4.30
ΦP	3.40	3.60	3.80
ΦP1	-	-	7.30
S	6.15BSC		

修订历史/Revision History:

修订 /Revision	主题 (自上次修订以来的主要变化) /Subjects (major changes since last revision)	日期 /Date
1.0	Initial Version	2020-11-27
2.0	Update the English and Chinese versions	2023-04

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